

李朱育 論文著述目錄

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(國內研討會)

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專業性雜誌文章

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4. 賴律臻, 林佑儒, 李朱育, "可應用於顯微鏡的光學式自動對焦法", 機械工業雜誌(審稿中)

獲獎紀錄

1. 八十八年中華民國光學工程學會博士學生論文獎 (得獎人: 李朱育)。
2. 八十九年中華民國計量工程學會計量論文獎 (得獎人: 李朱育, 蘇德欽, 許正治)。
3. 本實驗室碩士班研究生陳輝毓以「結合外差干涉術與光柵干涉術量測面內微小位移量之方法」(94年度國科會專案計畫補助)為題, 參加第一屆由田機器視覺獎創新類比賽 (比賽日期: 2006/09/30), 在近 60 組參賽隊伍中, 獲得第五名, 佳作獎金 4 萬元。並於 2006/10/19 全國 AOI 論壇與展覽會中 (交通大學) 頒發獎金及獎牌。(得獎人: 李朱育, 陳輝毓)

4. 本實驗室碩士班研究生周登科，在全場相位式表面電漿共振量測技術（95 年度國科會專案計畫補助）上的研究成果傑出，並發表 SCI 論文，當選本校 96 年度的傑出研究生。（但因登科選擇就業，放棄繼續深造，因而未能領取該獎項。）
5. 本實驗室碩士班研究生李貴宇，以「波長調制外差式光柵干涉儀之研究」（95-96 年度國科會專案計畫補助）為題，參加第四屆上銀科技機械碩士論文獎（比賽日期：2007/12/15）在近百位參賽者中，脫穎而出，獲得第四名，優等獎，獎金 30 萬元。（得獎人：李朱育，李貴宇）